

**Hierarchical identification of NBTI-critical gates in nanoscale logic**

**Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes; Jenihhin, Maksim** LATW2014 : 15th IEEE Latin-American Test Workshop : Fortaleza, Brazil, March 12th-15th, 2014 / [6] p. : ill

**Identification and rejuvenation of NBTI-critical logic paths in nanoscale circuits**

**Jenihhin, Maksim; Squillero, Giovanni; Tihhomirov, Valentin; Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes** Journal of electronic testing : theory and applications (JETTA) 2016 / p. 273-289 : ill <http://dx.doi.org/10.1007/s10836-016-5589-x>

**Identifying NBTI-critical paths in nanoscale logic**

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